

Single-Event Latch-Up (SEL) Automatic Detection and Recovery for the RT6804-1 Battery Stack Monitor

Kristen Chong, Tom Decker, Nathan Wendel, Amado Gomeri
 Analog Devices, Inc.
 7910 Triad Center Dr. Greensboro, NC, USA, 27409; 336-365-8461
 Kristen.Chong@analog.com

ABSTRACT

From previous SEE testing on the RT6804-1¹, a soft latch-up condition was identified with this device. When exposed to heavy ions, the RT6804-1's supply current can increase from the typical 12mA to 30mA or higher. This condition can be corrected by pulling all of the cell pins to GND. ADI wanted to provide an application circuit that automatically detects and corrects this SEL condition using minimal external components. This paper describes the mitigation circuit operation and SEE test results.

INTRODUCTION

The RT6804-1 is a 3rd generation multicell battery stack monitor that measures up to 12 series-connected battery cells with a total measurement error of less than 1.2mV. The cell measurement range of 0V to 5V makes the RT6804-1 suitable for most battery chemistries. All 12 cell voltages can be captured in 290 μ s, and lower data acquisition rates can be selected for high noise reduction. The RT6804-1 can be powered directly from the battery or an isolated supply.

When the RT6804-1 is upset by a heavy ion, the device no longer responds to SPI commands, and cell voltages are no longer readable. Occasionally, the device recovers on its own, but it can get stuck in this condition for extended periods. Analog Devices determined a circuit was needed to monitor and detect the increased current and trigger an automatic crowbar pull-down to clear the latch-up condition. This proposed mitigation circuit would require a current sense amplifier to monitor the current consumption of the device, a controlling device to interpret the current sense output and trigger the crowbar circuit, and a set of MOSFETs to pull all of the cell monitoring pins as well as V+ and VREG down to GND. For this application circuit to be viable for space customers, all components used are required to have direct or comparable space-qualified replacements. The circuit would also need to minimize the number of components to lower the overall size, weight, and power requirements of the solution.

MITIGATION CIRCUIT

The RH6105, a space-qualified current sense amplifier, was selected to monitor the current consumption of the RT6804-1 device. The input resistor network for the

RT6804 was configured to output a logic high voltage level when the monitored current is greater than 40 mA. The battery is connected directly to V+ and VREG through the RH6105 resistor network. The output of the current sense amp is connected directly to a digital pin on an ATmegaS128 MCU. This logic level change from the RH6105's output triggers an interrupt in the MCU to turn on the crowbar MOSFETs. Q17 in the circuit below disconnects the power (V+ and VREG) from the monitored device. The remaining MOSFETs connect the cell pins (pins C0-C12) of the RT6804-1 such that they are pulled down to GND to clear the latch-up. After 10 microseconds, the MOSFETs turn off to return the device to normal operation. This circuit avoids interrupting any other power buses in the end application because the RT6804-1 is directly powered from the battery.

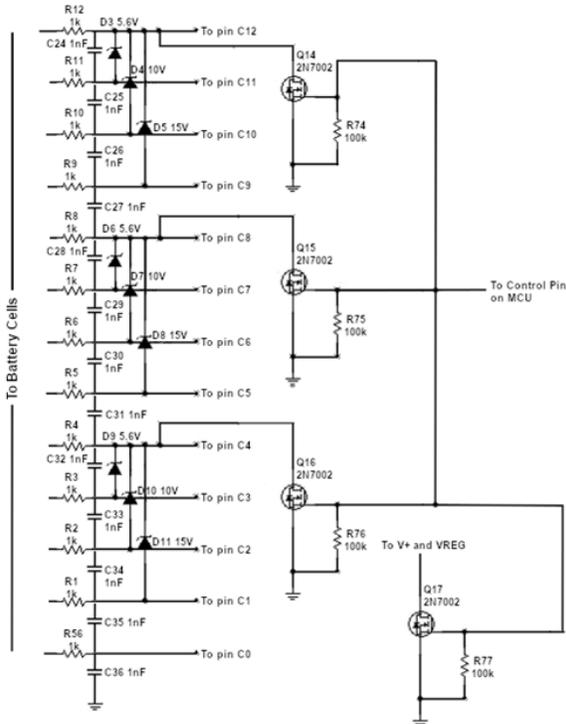


Figure 1: SEL Recovery System

EXPERIMENTS

Lab Testing

The mitigation circuit was evaluated in the lab prior to radiation testing to ensure the solution functioned as expected. Figure 2 and Figure 3 show the system's response to a forced current increase, including the output of the current sense amplifier.

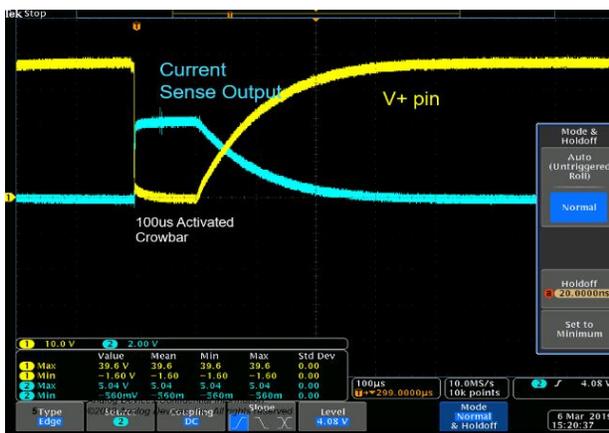


Figure 2: V+ Pin

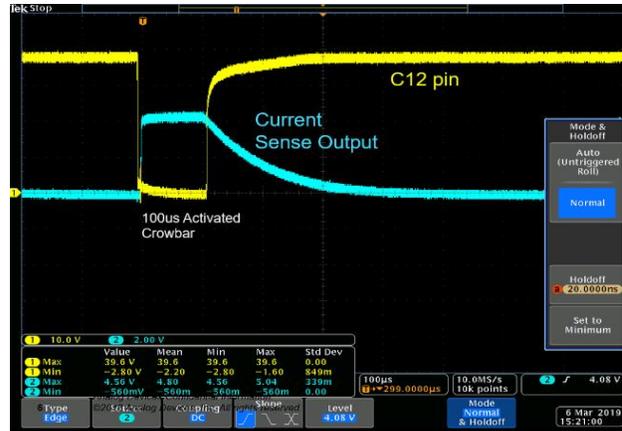


Figure 3: C12 Pin

Heavy Ion Testing

Heavy Ion testing was then performed at Texas A&M University Cyclotron Institute to verify the mitigation circuit performance under radiation. The UART interface with the microcontroller and a Python supply monitoring script were used to determine when the crowbar was activated. The microcontroller would then send a message over serial UART when it detected a current increase and activate the crowbar. The current spikes were observed on the supply monitor setup. Figure 4 shows device behavior with the SEL recovery circuit deactivated (MCU does not react to supply current increase). Figure 5 shows the device behavior after the recovery circuit was activated (MCU programmed to trigger the crowbar circuit). Figure 6 shows the recovery time for the mitigation circuit in more detail.

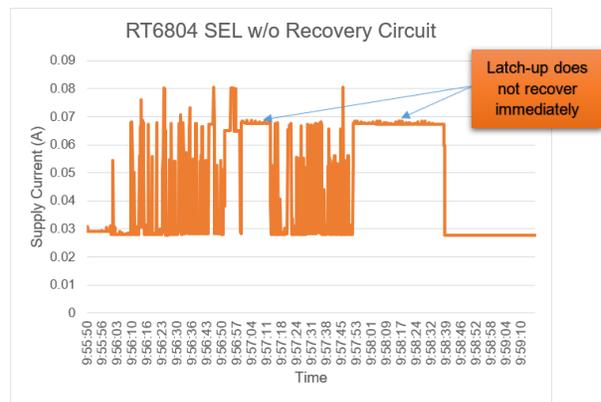


Figure 4: Device Response to Ions w/o SEL Recovery

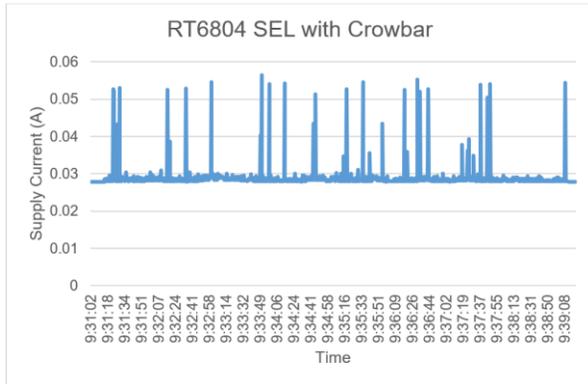


Figure 5: Device Response with SEL Recovery Active

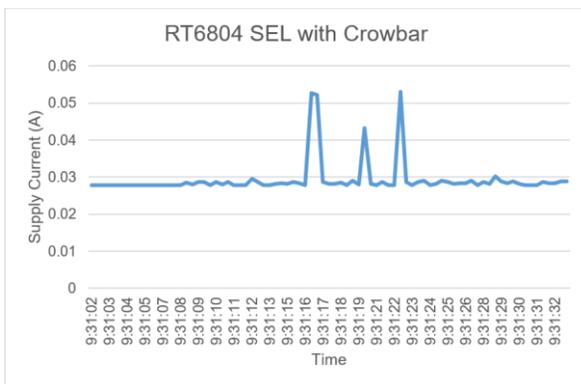


Figure 6: Device Response with SEL Recovery Active, Zoomed to Show Recovery Time

CONCLUSION

Analog Devices has designed and tested a single event latch-up mitigation circuit to support customers in implementing a robust solution for RT6804-1. Based on the results seen both in the lab and under heavy ion testing the mitigation circuit has been proven to reset current latch-ups.

References

1. S. C. Hart, P. G. Pandol, N. R. Wendel and R. Peralta, "Radiation Evaluation of Analog Devices' RT6804-1 Radiation Tolerant Multicell Battery Monitor," 2017 17th European Conference on Radiation and Its Effects on Components and Systems (RADECS), Geneva, Switzerland, 2017, pp. 1-4.